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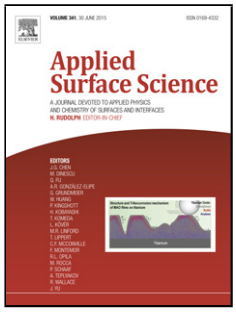

Title: Structural, morphological, optical and electrical properties of e-beam deposited nanocrystalline CdTe:Cu alloy thin films from mechanical alloyed samples

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Structural, morphological, optical and electrical properties of e-beam deposited nanocrystalline CdTe:Cu alloy thin films from mechanical alloyed samples

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Highlights:

- CdTe and CdTe:Cu powder were prepared by the process of ball milling.
- CdTe and CdTe:Cu thin films were deposited by electron beam evaporation method.
- Surface roughness decreases with increasing Cu concentration in CdTe thin films.
- Maximum transmittance shifts to lower wavelength for increasing Cu concentration.
- Raman intensity is influenced due to Cu doping.

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